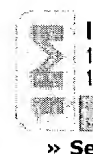


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# 1 [Compiler optimizations for eliminating barrier synchronization](#)

Chau-Wen Tseng

 August 1995 **ACM SIGPLAN Notices , Proceedings of the fifth ACM SIGPLAN symposium on Principles and practice of parallel programming**, Volume 30 Issue 8

Full text available: pdf(1.38 MB)

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This paper presents novel compiler optimizations for reducing synchronization overhead in compiler-parallelized scientific codes. A hybrid programming model is employed to combine the flexibility of the fork-join model with the precision and power of the single-program, multiple data (SPMD) model. By exploiting compile-time computation partitions, communication analysis can eliminate barrier synchronization or replace it with less expensive forms of synchronization. We show computation part ...

# 2 [Eliminating redundant barrier synchronizations in rule-based programs](#)

Anurag Acharya

 January 1996 **Proceedings of the 10th international conference on Supercomputing**

Full text available: pdf(920.79 KB)

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# 3 [Semantics of barriers in a non-strict, implicitly-parallel language](#)

Shail Aditya, Joseph E. Stoy, Arvind

 October 1995 **Proceedings of the seventh international conference on Functional programming languages and computer architecture**

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# 4 [A graph based approach to barrier synchronisation minimisation](#)

E. A. Stöhr, M. F. P. O'Boyle

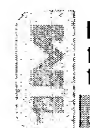
 July 1997 **Proceedings of the 11th international conference on Supercomputing**

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